IN THE CLAIMS:

These claims will replace all prior versions of claims in the present application.

1. (Original) A method of inspecting a target by tera-hertz wave spectroscopic measurement, comprising:

a spectroscopic measurement step of pre-measuring a spectrum [S] of tera-hertz wave absorbencies of a target component for a plurality of frequencies ranging about from 1 THz to 3 THz; and

an object spectroscopic step of irradiating an object with tera-hertz waves of the plurality of frequencies to measure absorbencies I of the object,

wherein presence and absence of the target component in the object is determined on the basis of the spectrum [S] of the absorbancy S and the spectrum [I] of the absorbancy I of the object.

2. (Original) A method of inspecting a target according to claim 1, comprising a density calculation step of calculating a target density [P] on the basis of the spectrum [S] of the absorbancy S and the spectrum [I] of the absorbancy I of the object.

3. (Original) A method of inspecting a target according to claim 2, the target spectroscopic step comprising a step of two-dimensionally scanning the object with the tera-hertz waves to measure a two-dimensional distribution [I] of the absorbancy I of penetration light,

and the density calculation step comprising a step of calculating a two-dimensional distribution [P] of the target density P.

4. (Currently Amended) A method of inspecting a target according to claim 2 ~~or 3~~, comprising a step of two-dimensionally displaying the two-dimensional distribution [P] of the target density P.

5. (Currently Amended) A method of inspecting a target according to claim 2~~, 3 or~~ 4, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M,

when N is equal to M, the two-dimensional distribution [P] of the target density P is calculated by $[P] = [S]^{-1}[I]$,

and when N is larger than M, the two-dimensional distribution [P] of the target density P is calculated by $[I] = [S][P]$, using a least square method.

6. (Original) An apparatus for inspecting a target using tera-hertz wave spectroscopic measurement, comprising:

a tera-hertz wave generation device (12) that generates tera-hertz waves (4) of a plurality of wavelengths;

a two-dimensional scan device (18) that scans an object (10) with the tera-hertz waves of the plurality of wavelengths,

a spectroscopic measurement device (14) that measures a two-dimensional distribution [I] of light absorbancy I of the object; and

a target density calculation device (16) that calculates a two-dimensional distribution [P] of a target density P on the basis of a pre-measured spectrum [S] of light absorbancy S of a target and the two-dimensional distribution [I] of the light absorbancy I.

7. (Original) An apparatus for inspecting a target by tera-hertz wave spectroscopic measurement, according to claim 6, comprising an image display device (20) that two-dimensionally displays an image of the two-dimensional distribution [P] of the target density P.

8. (NEW) A method of inspecting a target according to claim 3, comprising a step

of two-dimensionally displaying the two-dimensional distribution [P] of the target density P.

9. (NEW) A method of inspecting a target according to claim 3, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M,

when N is equal to M, the two-dimensional distribution [P] of the target density P is calculated by $[P] = [S]^{-1}[I]$,

and when N is larger than M, the two-dimensional distribution [P] of the target density P is calculated by $[I] = [S][P]$, using a least square method.

10. (NEW) A method of inspecting a target according to claim 4, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M,

when N is equal to M, the two-dimensional distribution [P] of the target density P is calculated by $[P] = [S]^{-1}[I]$,

and when N is larger than M, the two-dimensional distribution [P] of the target density P is calculated by $[I] = [S][P]$, using a least square method.